Supporting Information

Effects of surface characteristics of dielectric layers on polymer thin-film transistors obtained by spray methods

Hye-Yun Park,* Jun-Su Jin,† Sanggyu Yim,‡ Seung-Hwan Oh,§ Phil-Hyun Kang,∥ Si-Kyung Choi,∥* Sung-Yeon Jang‡*†

Hye-Yun Park,* Jun-Su Jin,† Sanggyu Yim,‡ Seung-Hwan Oh,§ Phil-Hyun Kang,∥ Si-Kyung Choi,∥* Sung-Yeon Jang‡*†

*Department of Materials Science and Engineering, Korea Advanced Institute of Science and Technology, Daejon 305-701, Republic of Korea

†Department of Chemistry, Kookmin University, 861-1, Jeongneung-Dong, Seongbuk-Gu, Seoul 136-702, Republic of Korea

‡Radiation Research Division for Industry and Environment, Korea Atomic Energy Research Institute (KAERI), 29 Geumgu-gil, Jeongeup-si, Jeollabuk-do 580-185, Korea

*Corresponding Author. Tel/Fax: +82-(2)-910-5768/4415

E-mail address: syjang@kookmin.ac.kr
Figure S1. Contact mode AFM images of (a) as-sprayed P3HT films on the OTS/SiO$_2$ (b) as-sprayed P3HT films on the SiO$_2$ (c) SSO treated P3HT films on the OTS/SiO$_2$ and (d) SSO treated P3HT films on the SiO$_2$. 
Figure S2. Output curve of (a) as-sprayed OFET on the OTS/SiO2, (c) SSO treated OFET on the OTS/SiO2. Transfer curve of (b) as-sprayed OFET on the OTS/SiO2, (d) SSO treated OFET on the OTS/SiO2. The closed symbol in transfer curve was obtained the forward scans and open symbols, backward scans.
**Figure S3.** TM-AFM images of as sprayed P3HT on the OTS/SiO$_2$